

CLAIMS

1. An integrated circuit testing apparatus, comprising:
an electrically insulative inclined support (20) having at least one
5 inclined surface (22); and
a plurality of electrically conductive, independently flexible
contact fingers (10) placed on a plane parallel to said inclined surface
(22), said contact fingers spaced apart from each other and substantially
level with said plane, said inclined surfaces (22) are angled such that
10 outer end tips (140) of said contact fingers (10) come into electrical
contact with load board contact pads (52) of said testing apparatus.
2. The integrated circuit testing apparatus according to claim 1, further
comprising an electrically insulative holder (30) rigidly joined at an
15 intermediate length of said plurality of contact fingers (10) such that an
inner end (12) of each said contact finger (10) projects in a cantilevered
fashion beyond said holder (30).
3. The integrated circuit testing apparatus according to claim 1, wherein
20 the said inclined support (20) has two inclined surfaces (22) located on
opposing sides of said inclined support (20) and such that the inclined
surfaces (22) mirror each other across a vertical plane.
4. The integrated circuit testing apparatus according to claim 1, wherein
25 the said inclined support (20) has four inclined surfaces (22) arranged in
a square formation as seen from a top down view.
5. The integrated circuit testing apparatus according to claim 1, wherein
30 the said inclined surface (22) is between 5° and 50° from a horizontal
plane.

6. The integrated circuit testing apparatus according to claim 1, wherein the said inclined surface (22) is between 10° and 20° from a horizontal plane.